



HAL
open science

Low-cost testing of a 2.4GHz ZigBee transmitter using standard digital ATE

Thibault Vayssade, Florence Azais, Laurent Latorre, François Lefèvre

► To cite this version:

Thibault Vayssade, Florence Azais, Laurent Latorre, François Lefèvre. Low-cost testing of a 2.4GHz ZigBee transmitter using standard digital ATE. ETS 2020 - 25th IEEE European Test Symposium, May 2020, Tallinn, Estonia. lirmm-03001537

HAL Id: lirmm-03001537

<https://hal-lirmm.ccsd.cnrs.fr/lirmm-03001537>

Submitted on 12 Nov 2020

HAL is a multi-disciplinary open access archive for the deposit and dissemination of scientific research documents, whether they are published or not. The documents may come from teaching and research institutions in France or abroad, or from public or private research centers.

L'archive ouverte pluridisciplinaire **HAL**, est destinée au dépôt et à la diffusion de documents scientifiques de niveau recherche, publiés ou non, émanant des établissements d'enseignement et de recherche français ou étrangers, des laboratoires publics ou privés.

Low-cost testing of a 2.4GHz ZigBee transmitter using standard digital ATE

T. Vayssade ^(1,2), F. Azaïs ⁽¹⁾, L. Latorre ⁽¹⁾, F. Lefevre ⁽²⁾

⁽¹⁾ LIRMM, Univ. Montpellier, CNRS, 161 rue Ada, Montpellier, France

⁽²⁾ NXP Semiconductors, 2 Espl. Anton Phillips, 14000 Caen, France

Abstract— In this abstract, we introduce an original technique that permits to perform the full RF test of a 2.4 GHz ZigBee transmitter using a standard digital channel instead of an expensive RF channel. The solution is based on a 1-bit under-sampled acquisition of the RF signal associated with a dedicated post-processing algorithm. Results obtained through laboratory experiments as well as an implementation in a real industrial test floor demonstrate that the technique permits to implement the standard tests required to evaluate the product quality, i.e. EVM measurement, spectral mask test and power measurement.

Keywords— RF test, ZigBee, OQPSK, 1-bit acquisition, digital signal processing, digital ATE, EVM measurement

I. INTRODUCTION

Testing cost of RF devices dedicated to the Internet Of Things is a major issue for semiconductor manufacturers. Classical techniques in use today consist in the use of Automatic Test Equipment (ATE) equipped with RF channels. However, such channels are very expensive and lead to very high-test cost. Moreover, these resources are generally available in small number reducing the multi-site efficiency. On the counterpart, digital channels are cheap and available in large number on a standard ATE. In this context, an interesting approach is to develop solutions that target RF testing using digital resources. In [1], a reference RF transceiver accompanied by an FPGA that interfaces the transceiver with a digital ATE is used to handle test signal generation/reception; in [2] a digital ATE system has been developed to test RF devices with QAM modulation.

Our objective is to develop a solution that relies on the use of a standard digital ATE channel in order to perform the test of ZigBee transmitters. Such circuits deliver a 2.4 GHz signal modulated with OQPSK format and half-sine pulse shaping. The conventional practice for testing these circuits is to use an ATE equipped with expensive RF channels. Such channels include high-performance hardware resources that perform down conversion and digitization the RF signal; digital signal processing procedures can then be applied on the digitized data stream to extract various signal characteristics and verify whether they comply with the product specifications. In case of a ZigBee product, the three main tests that are applied are power measurement, spectral mask test and EVM (Error Vector Magnitude) measurement.

II. PROPOSED TEST SOLUTION

The proposed test solution relies on the acquisition of the RF signal generated by the Device Under Test (DUT) with a standard digital channel as illustrated in Fig.1. A dedicated processing algorithm is then applied to this binary capture that permits to reconstruct an image of the original RF signal. Finally, classical digital signal processing procedures are

applied on the reconstructed RF signal to implement the standard tests required to evaluate the product quality.

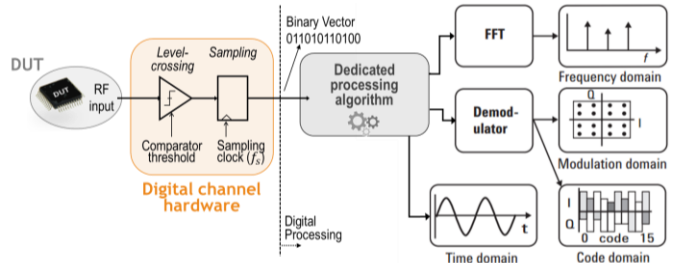


Fig.1. Proposed test solution based on the use of a digital tester channel

Basically, the hardware resources of a digital tester channel consist of a comparator and a latch; they therefore implement 1-bit conversion and sampling of the RF signal. The choice of the sampling frequency is an essential parameter of the test solution. Typically, standard digital channels have a maximum sampling rate of 1.6 GS/S, which means that under-sampling is mandatory. To comply with this constraint, the RF-modulated signal is sampled at a frequency closed to a submultiple n of the carrier frequency f_c ; the comparator threshold is set to approximately 70% of the expected RF signal amplitude. The resulting signal is a square-wave signal with a central beat frequency at $f_b = |nf_s - f_c|$, but that still contains relevant information concerning phase and amplitude variations of the original RF modulated signal. It is the role of the post-processing algorithm that has been developed to retrieve this information and reconstruct the RF modulated signal.

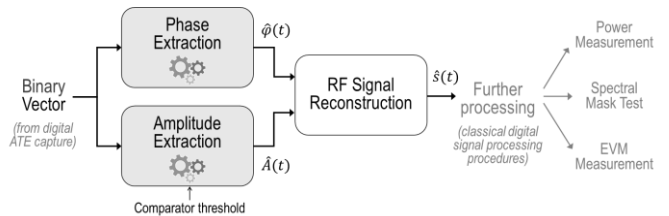


Fig.2. Simplified block diagram of the post-processing algorithm

More precisely, the algorithm involves three main blocks as illustrated in Fig.2. The first two blocks operate in parallel, one being dedicated to phase fluctuation extraction and the other to amplitude fluctuation extraction. These two blocks involve a succession of carefully designed operations that include filtering, interpolation, Hilbert transform, unwrapping, duty cycle to amplitude conversion (more details on the different operations can be found in [3]). The third block is dedicated to the reconstruction of the RF modulated signal, which is performed by adding the estimated amplitude fluctuation $\hat{A}(t)$ and the estimated phase fluctuation $\hat{\phi}(t)$ to an ideal RF sine-wave at carrier frequency: $\hat{s}(t) = \hat{A}(t) \cdot \sin(2\pi f_c t \pm \hat{\phi}(t))$.

